

**Search Notes**

Application/Control No.

10/666,845

Examiner

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Applicant(s)/Patent under  
Reexamination

FUJISE, TAKASHI

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	69	12/13/2004	NKV
330	252	12/13/2004	NKV
330	253	12/13/2004	NKV
330	255	12/13/2004	NKV
330	262	12/13/2004	NKV
330	263	12/13/2004	NKV
330	264	12/13/2004	NKV

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
CLASSES	ABOVE	5/10/2005	NKV

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	5/10/2005	NKV